

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	309	((select\$4 or choos\$4)near5 (read near3 (clock or strobe or signal)))with ((multiple or plural\$4)adj5 read)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/08 08:14
L2	3	I1 same ((transfer or transfer or transmit\$4 or transmission)near3 (speed or rate))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/08 07:26
L3	1	I1 and (((multiple or plural\$4)near3 read)with ((transfer or transfer or transmit\$4 or transmission)near3 (speed or rate)))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/08 07:34
L4	5	I1 and (((determin\$4 or detect\$4 or select\$4))with ((transfer or transfer or transmit\$4 or transmission)near3 (speed or rate)))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/08 08:14
L5	103	((transfer or transfer or transmit\$4 or transmission)near4 (encoded near3(data with clock)))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/08 07:34
L6	11	I5 and (((determin\$4 or detect\$4 or select\$4))with ((transfer or transfer or transmit\$4 or transmission)near3 (speed or rate)))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/08 07:34
L7	0	I6 and (((multiple or plural\$4)near3 read)with ((transfer or transfer or transmit\$4 or transmission)near3 (speed or rate)))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/08 08:15
L8	0	I5 and (((multiple or plural\$4)near3 read)with ((transfer or transfer or transmit\$4 or transmission)near3 (speed or rate)))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/08 07:35

L9	0	I5 and (((multiple or plural\$4)near3 read)same ((transfer or transfer or transmit\$4 or transmission)near3 (speed or rate)))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/08 07:35
L10	2	"4454499".pn.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/08 07:46
L11	100	"5268937" "4454499" "5912928" "5528183" "5841481" "6424631" "3775751" "6097716" "6222875" "6509988" "52260125,623,522" U5-6, 313,879.pn.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/08 07:48
L12	101	"5268937" "4454499" "5912928" "5528183" "5841481" "6424631" "3775751" "6097716" "6222875" "6509988" "52260125" "63138795"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/08 07:49
L13	22	("5268937" "4454499" "5912928" "5528183" "5841481" "6424631" "3775751" "6097716" "6222875" "6509988" "52260125" "63138795"). pn.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/08 08:14
L14	30	("6061747" "6320825" "5446765" "5850574" "6269127" "3864735" "4063291" "6104697" "5651014" "4796280" "6292621" "5412697" "5381397").pn.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/08 07:55
L15	6	"5226012"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/08 07:52
L16	4	("5226012" "5226012" "6313879").pn.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/08 07:54

L17	6	("5226012" "5623522" "6313879").pn.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/08 07:54
L18	23496	"713"/\$.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/08 08:19
L19	316	l18 and (((determin\$4 or detect\$4 or select\$4))with ((transfer or transfer or transmit\$4 or transmission)near3 (speed or rate)))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/08 08:19
L20	6	l18 and (((select\$4 or choos\$4)near5 (read near3 (clock or strobe or signal)))with ((multiple or plural\$4)adj5 read))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/08 08:21
L21	2	l19 and (((multiple or plural\$4)near3 read)with ((transfer or transfer or transmit\$4 or transmission)near3 (speed or rate)))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/08 08:19
L22	92419	"369"/\$.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/08 08:23
L23	518	l22 and (((determin\$4 or detect\$4 or select\$4))with ((transfer or transfer or transmit\$4 or transmission)near3 (speed or rate)))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/08 08:23
L24	4	l23 and (((multiple or plural\$4)near3 read)with ((transfer or transfer or transmit\$4 or transmission)near3 (speed or rate)))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/08 08:24

L25	9	I22 and (((select\$4 or choos\$4)near5 (read near3 (clock or strobe or signal))))with (((multiple or plural\$4)adj5 read))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/08 08:24
L26	102048	"360"/\$.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/08 08:25
L27	530	I26 and (((determin\$4 or detect\$4 or select\$4))with ((transfer or transfer or transmit\$4 or transmission)near3 (speed or rate))))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/08 08:25
L28	25	I26 and (((select\$4 or choos\$4)near5 (read near3 (clock or strobe or signal))))with (((multiple or plural\$4)adj5 read))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/08 08:26
L29	3	I27 and (((multiple or plural\$4)near3 read)with ((transfer or transfer or transmit\$4 or transmission)near3 (speed or rate))))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/08 08:27
L30	2	I28 and (((determin\$4 or detect\$4 or select\$4))with ((transfer or transfer or transmit\$4 or transmission)near3 (speed or rate))))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/08 08:26
L31	65870	"348"/\$.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/08 08:28
L32	17	I31 and (((select\$4 or choos\$4)near5 (read near3 (clock or strobe or signal))))with (((multiple or plural\$4)adj5 read))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/08 08:28

L33	767	I31 and (((determin\$4 or detect\$4 or select\$4))with ((transfer or transfer or transmit\$4 or transmission)near3 (speed or rate)))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/08 08:26
L34	0	I32 and I33	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/08 08:26
L35	2	I33 and (((multiple or plural\$4)near3 read)with ((transfer or transfer or transmit\$4 or transmission)near3 (speed or rate)))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/08 08:28
L36	57397	"375"/\$.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/08 08:28
L37	7	I36 and (((select\$4 or choos\$4)near5 (read near3 (clock or strobe or signal)))with ((multiple or plural\$4)adj5 read))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/08 08:51
L38	4	I36 and (((multiple or plural\$4)near3 read)with ((transfer or transfer or transmit\$4 or transmission)near3 (speed or rate)))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/08 08:28
L39	42	(decoder or encoder)with ((detect\$4 or determin\$5)near3 (transfer adj2(speed or rate)))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/08 08:50
L40	1	I39 and (((select\$4 or choos\$4)near5 (read near3 (clock or strobe or signal)))with ((multiple or plural\$4)adj5 read))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/08 08:51

L41	1	I39 and (((select\$4 or choos\$4)near5 (read near3 (clock or strobe or signal))))same ((multiple or plural\$4)adj5 read))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/08 08:51
L42	1	I39 and (((select\$4 or choos\$4)near5 (read near3 (clock or strobe or signal))))and ((multiple or plural\$4)adj5 read))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/08 08:51

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1 Corona and breakdown characteristics between sphere electrode with protrusion and plane electrode under negative pulse voltage in N/sub gas
Ueno, H.; Sakamoto, N.; Hoshida, T.; Nakayama, H.;

 Dielectrics and Electrical Insulation, IEEE Transactions on [see also Electrical Insulation, IEEE Transactions on] ,Volume: 11 , Issue: 6 , Dec. 2004
 Pages:1065 - 1072

[\[Abstract\]](#) [\[PDF Full-Text \(1659KB\)\]](#) **IEEE JNL**
2 Impurity-profile-based threshold-voltage model of pocket-implanted MOSFETs for circuit simulation
Ueno, H.; Kitamaru, D.; Morikawa, K.; Tanaka, M.; Miura-Mattausch, M.;

 Mattausch, H.J.; Kumashiro, S.; Yamaguchi, T.; Yamashita, K.; Nakayama, N.
 Electron Devices, IEEE Transactions on ,Volume: 49 , Issue: 10 , Oct. 2002
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[\[Abstract\]](#) [\[PDF Full-Text \(339KB\)\]](#) **IEEE JNL**
3 Importance of ballistic carriers for the dynamic response in sub-100 MOSFETs
Okagaki, T.; Tanaka, M.; Ueno, H.; Miura-Mattausch, M.;

 Electron Device Letters, IEEE ,Volume: 23 , Issue: 3 , March 2002
 Pages:154 - 156

[\[Abstract\]](#) [\[PDF Full-Text \(237KB\)\]](#) **IEEE JNL**
4 Fabrication of thick film magnetic cores for high frequency using LIG process
Takimoto, S.; Ueno, H.; Sugiyama, S.; Yamaguchi, M.; Baba, M.; Arai, K.-I.;

 Magnetics, IEEE Transactions on ,Volume: 37 , Issue: 4 , July 2001
 Pages:2888 - 2890

[\[Abstract\]](#) [\[PDF Full-Text \(160KB\)\]](#) **IEEE JNL**
5 Anomalous creeping flashover characteristics in N₂/SF₆ mixed gas

under single pulse voltage

Ueno, H.; Sakamoto, N.; Nakayama, H.;

Dielectrics and Electrical Insulation, IEEE Transactions on [see also Electrical Insulation, IEEE Transactions on] ,Volume: 8 , Issue: 2 , April 2001

Pages:195 - 202

[\[Abstract\]](#) [\[PDF Full-Text \(752KB\)\]](#) IEEE JNL

6 An experimental M2DFE detector

Yuan Xing Lee; Qingwei Jia; Jianjiang Wang; Qing Li; Lei Bi; Ueno, H.; Mutoh,

Magnetics, IEEE Transactions on ,Volume: 35 , Issue: 5 , Sept. 1999

Pages:2292 - 2294

[\[Abstract\]](#) [\[PDF Full-Text \(260KB\)\]](#) IEEE JNL

7 A method for suppressing error propagation in (1,7) MDFE detectors

Ueno, H.; Sugawara, T.; Shimoda, K.; Mutoh, H.;

Magnetics, IEEE Transactions on ,Volume: 35 , Issue: 5 , Sept. 1999

Pages:2289 - 2291

[\[Abstract\]](#) [\[PDF Full-Text \(320KB\)\]](#) IEEE JNL

8 PdPtMn/CoFeB synthetic ferrimagnet spin-valve heads

Kanai, H.; Kanamine, M.; Hashimoto, A.; Aoshima, K.; Noma, K.; Yamagishi,

Ueno, H.; Uehara, Y.; Uematsu, Y.;

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[\[Abstract\]](#) [\[PDF Full-Text \(340KB\)\]](#) IEEE JNL

9 Rigid disk medium for 20 Gb/in² recording demonstration

Sato, K.; Yoshida, Y.; Yamagishi, M.; Ueno, H.; Akimoto, H.; Abarra, E.N.; Ka

H.; Uehara, Y.; Okamoto, I.; Uematsu, Y.;

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Pages:2655 - 2657

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10 An experimental MDFE detector

Hong, J.; Yuan Xing Lee; Mutoh, H.; Qicheng Sun; Ueno, H.; Jianjiang Wang;

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11 A novel proportional counter made of a capillary plate

Tamura, T.; Sakurai, H.; Noma, M.; Gunji, S.; Ueno, H.; Tsukahara, M.; Ham

M.;

Nuclear Science, IEEE Transactions on ,Volume: 43 , Issue: 3 , June 1996

Pages:1533 - 1538

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12 The energy resolution of proportional counters with thin anode diameters down to 5 μm

Tokanai, F.; Sakurai, H.; Noma, M.; Gunji, S.; Ueno, H.; Anzai, T.; Kato, F.; Hoshina, T.;

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13 Arc-discharge mode and interruption performance in vacuum switch tubes

Toya, H.; Hayashi, T.; Okumura, M.; Yorita, M.; Ueno, H.;

Power Delivery, IEEE Transactions on , Volume: 7 , Issue: 1 , Jan. 1992
Pages:324 - 331

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14 Polymer based smart flexible thermopile for power generation

Hasebe, S.; Ogawa, J.; Shiozaki, M.; Toriyama, T.; Sugiyama, S.; Ueno, H.; Itoigawa, K.;

Micro Electro Mechanical Systems, 2004. 17th IEEE International Conference (MEMS) , 2004
Pages:689 - 692

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15 Study of partial discharge localization methods for EHV prefabricated joint

Chen Min; Urano, K.; Kato, A.; Sakaguchi, Y.; Okamoto, G.; Ueno, H.; Hirotsu, Jinno, A.; Okada, M.; Yoshikawa, N.;

Power Engineering Society Summer Meeting, 2000. IEEE , Volume: 1 , 16-20 2000
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16 Fabrication of sub-micron structures with high aspect ratio for MEM using deep X-ray lithography
Ueno, H.; Nishi, N.; Sugiyama, S.;

Micro Electro Mechanical Systems, 2000. MEMS 2000. The Thirteenth Annual International Conference on , 23-27 Jan. 2000

Pages:596 - 601

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17 Direct writing for three-dimensional microfabrication using synchrotron radiation etching
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Wakabayashi, S.; Koide, T.; Toshine, N.; Yamane, M.; Ueno, H.;

Design Automation Conference, 2000. Proceedings of the ASP-DAC 2000. Asia South Pacific , 25-28 Jan. 2000

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19 Study on fabrication of high aspect ratio microparts using the LIGA process
Ueno, H.; Hosaka, M.; Zhang, Y.; Tabata, O.; Konishi, S.; Sugiyama, S.;

Micromechatronics and Human Science, 1997. Proceedings of the 1997 International Symposium on , 5-8 Oct. 1997

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20 An Experimental MDFE Detector

Bi, L.; Hong, J.; Lee, Y.X.; Mutoh, H.; Sun, Q.C.; Ueno, H.; Wang, J.J.; Wood,
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 Pages:CR-05 - CR-05

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21 Development of Nissan's ASV

Sugasawa, F.; Ueno, H.; Kaneda, M.; Koreishi, J.; Shirato, R.; Fukuhara, N.;
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 Pages:254 - 259

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22 A compact SR beamline for fabrication of high aspect ratio MEMS microparts

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 International Symposium , 2-4 Oct. 1996
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23 Low-k fluorinated amorphous carbon interlayer technology for quasi-micron devices

Matsubara, Y.; Endo, K.; Tatsumi, T.; Ueno, H.; Sugai, K.; Horiuchi, T.;
 Electron Devices Meeting, 1996., International , 8-11 Dec. 1996
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24 Unique corona and creeping flashover characteristics in N_2/SF_6 mixtures on highly nonuniform narrow gap

Ueno, H.; Kawano, T.; Nishikawa, T.; Nakayama, H.;
 Properties and Applications of Dielectric Materials, 2003. Proceedings of the 71
 International Conference on , Volume: 1 , 1-5 June 2003
 Pages:232 - 237 vol.1

[\[Abstract\]](#) [\[PDF Full-Text \(456KB\)\]](#) IEEE CNF

25 Design and fabrication of flexible thermopile for power generation

Hasebe, S.; Ogawa, J.; Toriyama, T.; Sugiyama, S.; Ueno, H.; Itoigawa, K.;
 Micromechatronics and Human Science, 2003. MHS 2003. Proceedings of 2003
 International Symposium on , 19-22 Oct. 2003
 Pages:287 - 291

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